



DTIC CORM 70A

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Technical Report

TECHNICAL REPORT INSTRUMENTATION VALIDATION

May 1979



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May 1979

Prepared For

ARMAMENT DEVELOPMENT AND TEST CENTER EGLIN AIR FORCE BASE, FLORIDA

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1. INTRODUCTION

This report is written to fulfill the requirements of Data Item B004 of Contract No. F08635-77-C-0293. The report covers the work performed under Task 7 - Validate Instrumentation of Contract Modification P00010. This work was performed during March and April 1979 at the GVT Facility at Eglin Air Force Base.

An analytic and test validation was performed on the GVT Facility instrumentation. The purpose of the test was to determine the capability of the GVT System to perform its intended mission of dynamic analysis of aircraft structures. Each element of the system was examined to determine its individual function as well as its intended and unintended interaction with every other element of the system. The system was tested for signal input accuracy, cable integrity, grounding, noise susceptibility, and output signal integrity. All components were found to be wellmaintained and functioning properly. The only discrepancies found in the system relate to system analog grounding. Recommended corrective measures to eliminate these discrepancies are outlined.

With the implementation of the recommendations contained in this report, the GVT should be an excellent tool for dynamic analysis of aircraft structures and the instrumentation should provide constant, repeatable results under all test conditions.

2. WORK APPROACH

The facility validation task was broken down into the following sequence of individual tasks: Problem Definition, System Definition, Test Development, Testing, Test Results Analysis, Retest and Validation, and Recommendations for Corrective Action.

A meeting was held with GVT personnel to obtain a better understanding of the function of the system and the way it was utilized. Areas discussed included normal system configuration, test setup, problem areas encountered in testing, system performance, and test results validity. From these discussions it was determined that an independent evaluation of the ability of the system to provide accurate, repeatable, and reliable results was needed.

2.1 PROBLEM DEFINITION

Based on the requirement for an independent evaluation of the GVT instrumentation system performance, further discussions were held to determine the problems that had been experienced in the past and to try to classify these problems as to their cause and impact on system performance. The following areas were identified as potential areas for further evaluation and test:

- Noise on some transducers under some test conditions
- Lack of calibration data on
 - Input preamplifiers
 Output power amplifiers
- Uncertainty over the effects of cable grounding
- Uncertainty over the effects of system ac power wiring
- Low-level shaker excitation with no input command when shaker amplifiers were powered from test floor.

2 - 1

2.2 SYSTEM DEFINITION

To properly understand the functional relationship existing between components of the GVT instrumentation, functional diagrams of the input and output signal flow were developed. These were reviewed with the GVT personnel to clarify the exact methodology used in interconnecting various elements and to obtain their insight into how various operating configurations contributed to system performance. These functional diagrams are presented in Figure 2-1 (signal input block diagram) and Figure 2-2 (excitation outputs block diagram). These diagrams were then used in defining all testing approaches and recommendations.

2.3 TEST DEVELOPMENT

A test approach was developed that would utilize the system as configured to examine the problem areas identified as well as provide an insight into any other system performance restrictions that might exist. The integrity of all input and output signals should be verified as well as the cabling. To accomplish this, four basic tests were developed, as shown in Table 2-1.

QUANTITY	COMPONENT	TEST TO BE PERFORMED
200	Cables	Short-circuit resistance, insulation resistance
32	Input Preamplifiers	Gain, frequency response, distortion
4	Power Amplifiers	Gain, frequency response, distortion
	System	Grounding and inter-rack ambient noise level

TABLE 2-1. FOUR BASIC TESTS FOR GVT

Based on the results of these tests, a full-scale examination of the system would be conducted to determine how each component contributed to the total system performance. The results of these tests are covered under test results (Section 3) and the test data are contained in the attached appendices.





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3. TESTING AND TEST RESULTS

The following paragraphs discuss the detailed testing performed on the GVT instrumentation as well as the general conclusions reached about the performance of the individual components being tested.

3.1 CABLE TEST

An easily implementable and repeatable test was required to verify the integrity of all coaxial cables from the test floor to the system patch panel. After examination of the characteristics of the cable used (RG58, RG174, and Microdot Lo Noise) and the test frequencies of interest (0 to 200 Hz), it was determined that the characteristics that could be most detrimental to test results were dc resistance of the coaxial cable and insulation resistance.

The dc resistance test was conducted with one end of the cable shorted. This allowed the measurement of shield and center conductor resistance as well as all terminations (crimp and solder) in the cable run. As shown in the test results, the resistance is very repeatable from cable to cable. Table 3-1 lists the range of acceptable values for various configurations as well as those cables that are suspect and that should be examined for poor terminations.

FROM	то	ACCEPTABLE VALUE (ohms)	SUSPECT CABLE NO.
Floor	Patch Panel	4.3 to 5.9	3, 30, 40, 52, 86
Transducer	Patch Panel	9.0 to 10.0	40, 52
Floor	Breakout Panel	1.2 to 1.6	152

TABLE 3-1. RANGE OF ACCEPTABLE VALUES

The Meggar test was conducted with the cable unterminated. This test measures the conductor-to-shield insulation resistance at 500 Vdc and will indicate shortened cables, crushed insulation, and contaminated connectors and terminations. Any value over 1 kMohm is acceptable. Cable No. 40 was found to be bad. Cables 184 to 196 exhibited a higher (1.6-ohm) resistance than cables 101 to 185, probably because a different brand of connector was used. This should present no problems with signal transmission.

Appendix A contains the test procedure and all test data taken.

3.2 INPUT PREAMPLIFIER TEST

The input preamplifiers were tested to determine their ability to accurately amplify and reproduce the transducer signal. Each amplifier was tested at 30, 300, and 600 mV input signal at the following frequencies: 2, 10, 20, 30, 40, 80, 140, and 200 Hz. The output amplitude was measured and the amplifiers were found to have a gain of 10.6 to 1 uniformly. This gain rolled off to 10.3 to 1 at 2 Hz at all amplitudes and increased to 11 to 1 at 600 mV input. These changes are insignificant to the testing being conducted.

The distortion of each amplifier was measured at 300 mV input at 20, 80, and 200 Hz and was found to be less than 0.4% for all amplifiers. This level of distortion is insignificant to the testing being conducted by the facility.

Appendix B contains the test procedure and all test data taken.

3.3 GROUNDING TEST

After preliminary investigations of system performance and discussion of previous system problems with GVT Facility personnel, it was determined that the potential existed for ground noise between components of the GVT Facility. The tests of Appendix C were conducted. These tests indicated that the primary potential ifference existed between the test stand and the instrumentation. These tests also indicated that insufficient grounding existed between GVT components. As shown by the test data, addition of a ground strap reduced this noise by 66%.

Subsequent testing of ground potential differences and ground noise using the power spectral density measurement capability of the GVT computer revealed that 60-Hz ac power ground potential differences were the cause of the noise measured in the above test. Inadvertent shorting of the transducer-case-to-test-stand ground would then be the primary cause of error in GVT testing. The correction of this problem is addressed in Section 4.

3.4 POWER AMPLIFIER TEST

The power amplifiers were tested to determine their ability to accurately and repeatably provide the drive signal to the shakers at the required power levels. Each amplifier was tested at output power levels of 10, 50, and 100 W at excitation frequencies of 2, 10, 20, 30, 40, 80, 140, and 200 Hz. They were all found to have a flat response to 10 Hz, with some power amplification at 2 Hz. This amplification is not caused by the amplifier but by the dc resistance of the shaker coil at this low frequency.

The amplifier distortion measured at 50 W output power at 20, 100, and 200 Hz was found to be less than 0.6%. This distortion level is insignificant to the testing being conducted. The phase shift was measured at 20, 100, and 200 Hz at 100 W output power and was found to be zero at the higher frequencies and only 7 deg at 20 Hz. This phase shift should not affect test results or excitation characteristics.

3.5 TEST RESULTS ANALYSIS

The test data contained in the appendices were examined to determine if each component was making a proper contribution to GVT instrumentation performance. The only area identified that required further

3-3

investigation was system grounding. The potential difference between system components, especially between the test stand and the preamplifier rack, was much too high for good, consistent low-level signal measurement.

All other component testing verified that the equipment was functioning properly and was fully capable of performing the GVT mission.

3.6 RETEST AND VALIDATION

A retest of the input system with transducers connected was conducted to examine the effect of ground noise found in initial testing on system performance. This test was conducted in two phases: 1) ground potential measurement and 2) transducer signal impact.

The ground potential between the aircraft grounding lugs in the test floor and the legs of the test stand was measured. The potential between lugs ranged from 1 to 5 mV rms and between lugs and the test stand ranged from 7 to 12 mV rms. This measurement indicates that the test stand has no common ground and that the test stand is not connected to the grounding lugs in the floor. The structural modifications to be made to the test stand along with the recommendations made later in this report should reduce this noise to acceptable levels (1 to 3 mV rms).

The system was then configured for a power spectral density (PSD) test. An accelerometer and load cell were connected to two input amplifier channels. The transducers were held on the test floor on an isolation pad and the signal output was monitored at the transducer power supply with an oscilloscope. The noise level from both transducers was less than 1 mV peak-to-peak. The computer-run PSD test indicated that what coherent noise existed was centered at 60 Hz.

The transducer cases were individually shorted to the test stand. The noise increased to 50 mV peak-to-peak, with the primary frequency at 60 Hz and a secondary contribution at 180 Hz (third harmonic). When both cases were shorted together and then shorted to the test stand, the noise was reduced to 40 mV peak-to-peak.

3-4

With the transducer cases shorted together and to the test stand, an 8 AWG (3 No. 12 AWG) ground strap was connected between the test stand and the preamplifier rack. The noise level was reduced to 10 mV peak-topeak with the same 60- and 180-Hz frequency content.

Based on these measurements, it was concluded that the only problem with the system was one of 60-Hz power grounding and that the system, through its PSD measurement capability, could be configured to monitor its own ground noise condition. No problems should be encountered with the present configuration as long as care is taken to ensure that all transducers are isolated from the test stand ground.

4. CONCLUSIONS AND RECOMMENDATIONS

4.1 CONCLUSIONS

The GVT instrumentation as configured will perform accurate, repeatable tests and will provide reliable, consistent results provided all transducers are electrically isolated from the test item. As currently configured, up to 50 mV peak-to-peak of 60-Hz noise will be injected on transducer liners that are shorted to the test item or the structure.

During testing, it was demonstrated that these noise levels could be substantially reduced by revision of the system grounding. The revision to system grounding and isolation are the major recommendations derived from these test and analysis efforts. Implementation of these recommendations should remove all test anomalies.

Measures should be taken to reduce this 60-Hz noise by reducing the ground potential difference between system elements.

4.2 RECOMMENDATIONS

Only two recommendations for revisions to equipment or procedures have been identified as potential improvements to system performance. The basic system, including all cables, transducers, and electronics, was found to be sound and properly maintained. The recommendations deal with reduction of system 60-Hz ground differential voltage and with the isolation of all test transducers.

4.2.1 Transducer Isolation

It was found that accelerometers are generally installed on isolation studs; however, no attempt is made at present to verify that ground isolation is achieved. A procedure should be instituted whereby each transducer's isolation is verified with an ohmmeter prior to connection of that transducer's cable.

4-1

The load cell placed between the shaker and the test specimens is not currently isolated since it is bolted directly to the load transfer pads. A nonconductive shim should be placed between this pad and the test specimens to ensure electrical isolation. This isolation should be verified prior to connection of the load cell cable in the same manner as the transducer. If a nonisolated shaker is used, then similar precautions should be taken between the shaker and the load cell.

4.2.2 60-Hz Noise and Grounding

The 60-Hz noise can be traced to two sources: 1) the lack of a common analog ground system and 2) the lack of a common instrumentation power source. Because the GVT facility was installed in an existing facility, not all ac power is derived from a single power panel with common ground. This presents a condition wherein chassis ground differences can develop and vary according to electrical loads in other parts of the building not controlled by GVT Facility personnel. To alleviate this problem, the ac wiring servicing the GVT Facility should be revised to provide a common power distribution point for all instrumentation with no other, nonfacility equipments attached.

No consideration has been given to establishing a common analog ground for the system separate from the ac third-wire safety ground. Tests have shown (Appendix C) that ground noise can be substantially reduced by installation of an analog grounding system. The recommended grounding scheme is shown in Figure 4-1 and implemented as follows:

- A ground bus should be installed in the signal power supply and amplifier rack.
- A 6 AWG wire should be run from a welded lug on the test stand to the ground bus.
- A 6 AWG pigtail should be provided from the test stand ground lug to the test specimens.
- An 8 AWG wire should be run from the ground bus to each of the other equipment rack frames.
- A 16 AWG wire should be run from the ground bus to the ground jack on each transducer power supply.

4-2



FIGURE 4-1. RECOMMENDED SIGNAL GROUND SCHEME

This grounding scheme should establish an analog ground system independent of ac third-wire grounding and substantially reduce 60-Hz noise in the system.

4.2.3 Cable Retest

At least once a year the test of Appendix A (Cable Continuity and Impedance) should be rerun to reverify the integrity of all cables, especially those on the test floor. This test can be run in approximately 8 hours and will identify any damaged cables.

Whenever an individual cable is suspect, the test can be run to the cable in a matter of minutes and the problem corrected before continuing testing.

4.2.4 Automatic System Checkout

In addition to the above-mentioned recommendations, an automatic pre- and post-test checkout should be considered. The H.P. computer has the capability of acquiring and testing all transducer channels automatically. This capability can be used to run a power spectral density measurement on all transducers prior to activation of the shakers. This test can be set to flag any transducer that shows a 60-Hz frequency or other component that is above the system quiescent noise level (established after all system modifications are complete). The verification can be rerun at the completion of each test or after each shaker reconfiguration, thereby verifying that no degradation in system grounding and isolation has occurred during the test. This test should be run with the programmable filter in the bypass mode.

APPENDIX A. RESISTANCE TEST

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The purpose of this test is to verify the integrity of all wiring from the test floor to the patch panel. Using the equipment as shown in figure 1______ conduct the following test and record the results in table 1_____.

- o Short Circuit Resistance: Connect a shorting plug to the cable at the patch panel and measure the total resistance, shield to center conductor at the floor end of the cable. For those wires stoping at the monitor panel - install the shorting plug at that point.
- Megohn Test: With all patches and shorting plugs removed, measure the open circuitry resistance of the wires with a megohmmeter.



FIGURE 1 755 EANIMENT 3600 A Digital Multimeter SN 585307 (Fluke) 1620 Megohmeter SN 709 (Freed)

TABLE 1

FLOOR WIRE NO.	RESISTANCE WITH SHORT AT PATCH/1	PANEL	$\frac{\text{MEGGAR}}{\text{TEST}} \left(\checkmark = \infty \right)$
/	5.5	•	1.4 K MEG
2	4,6		
3	8.7		+
	4.6		
5.	4,5		20K N=G
6	4,5	÷-	1.8 K rEG
7.	4.5	· .	
8	4.5		1.4 KMEG
9.	4,4		\checkmark
10	4,3		
	4.4	. *	5K MEG
12	49		3.2 K MEG
13	4,3		
14	4.7		50K N'EG
15	4.4	<u></u>	1.5K MEG
16	4,3	······	
17	4.8	N 11	
18	48		
19	4.9		\checkmark
20	4.7		13.5K MEG
21	4.4		IIK MEG
22	4.9		GK MEG

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TABLE 1

FLOOR WIRE NO.	RESISTANC SHORT AT	CE WITH PATCH/PANEL	MEGGAR TEST	_
23	4.3	1. 4	\checkmark	
24	4.3	u	1	
25	4,3			
26	4,3			_
21	5,0		1.6K MEG	_
28	5,2			_
29	4,3		ISK MEG	-
30	9.5		\checkmark	- -
31	4.3	9,0	\checkmark	-
32	4.3	9,0	1.5 K MEG	-
33	4,6	9,3	\checkmark	_
34	4.3	9.0	\checkmark	-
35	4,3	9.0	2K MEG	_
36	4.3	9,0	\checkmark	_
37	4.3	9.0	5K MEG	_
38	4,3	9,0		
39	4.7	9,5		-
40	6.3	11.6	low resistance	-
41	4,8	9,6	\checkmark	-
42	4,4	9,1	\bigvee	
43	4.8	9.5	HOK MES	
44	5.0	9,7		

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TABLE 1

FLOOR WIRE NO.	RESISTANCE SHORT AT 1	E WITH PATCH/PANEL	MEGGAR TEST
45	4,4	9.1	\checkmark
46	5,7	10,4	3K MEG
47	51	9,8	\checkmark
48	4.7	9,4	IK MEG
49	. 4.3	9,0	
50	4.4	9.1	
51	4,3	8,9	5K MEG
52	11.9	16,6	5K MEG
53	4,4	9,1	
54	4.9		\checkmark
55	4.8		IK MEG
56	4.6		
57	4.4		\checkmark
58	4.8		20K MEG
59	4.6		
60	4.6		5K MEG
61	5.9		
62	4,3		I3K MEG
63	4.8		
64	4.4		
65	5,4		IDK MEG
66	4.5		GK MEG

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TABLE 1

FLOOR WIRE NO.	RESISTANCE WITH SHORT AT PATCH/PANEL	MEGGAR TEST
67	4,6	2.8 K MEG
68	4,7	5K MEG
69	4.5	
70	4,5	4K MEG
71	4.5	
72	4,6	5K MEG
73	4.7	7K MEG
74	4,5	4K MEG
75	4.5	5K MEG
76	5.0	
77	4.5	
78	4,6	HK MEG
79	4.6	7K MEG
80	4.6	4K MEG
81	4,6	
82	5,0	\checkmark
83	4.5	5K MEG
84	4.6	IK MEG
85	4.6	\checkmark
86	13.7	\checkmark
87	4.6	20K MEG
88	4.6	GOO MEG

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TABLE 1

FLOOR WIRE NO.	RESISTANCE WITH SHORT AT PATCH/PANEL	MEGG AR TEST
- 89	4.6	
90	4.6	
91	4,6	\checkmark
92	4,6	
93	4.5	600 MEG
94	4.6	\checkmark
95	4.5	5K MEG
96	4,5	\checkmark
97	4.8	\checkmark
98	4,6	
99	4,5	
100	4.9	\checkmark
/01	1.2	
102	1.2	IDK MEG
103	1.2	20K MEG
104	1.2	
105	1.2	
106	1.2	17K MEG
_157	142	\checkmark
108	1.2	IK MEG
109	1.2	3K MEG
110	1.2	\sim

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TABLE 1

FLOOR WIRE NO.	RESISTANCE WITH SHORT AT PATCH/PANEL	MEGGAR TEST
	1.2	IOK MEG
112	1.2	1.8 K M.EG
// 3	1.2	\checkmark
114	1.2	4K MEG
115	1.2	\checkmark
116	1.2	\checkmark
117	1.47	\checkmark
118	1.2	
119	1.2	20K MEG
120	1.2	\checkmark
121	1.2	
122	1.2	\checkmark
123	1.2	GK MEG
124	1.16	GK MEG
125	152	
126	1.2	\checkmark
127	1.2	
128	1.2	IK MEG
129	1.2	IOK MEG
130	1.2	\checkmark
131	1.2	\mathbf{V}
/32	1.2	1.3 K MEG

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TABLE 1

FLOOR WIRE NC.	RESISTANCE WITH SHORT AT PATCH/PANEL	MEGGAR TEST
133	1,2	IOK MEG
134	1.2	20K MEG
135	1.2	2K MEG
136	1.2	1.6 K MEG
137	1.2	\checkmark
138	1.28	
	1.2	
140	1.2	GK MEG
141	1.2	1.2K MEG
142	1.2	4.5K MEG
/+3	1.2	
144	1.2	
145	1.2	5K MEG
146	1:2	\checkmark
147	12	2.2K MEG
148	1.2	
149	1.2	
150	1.2	II.GK MEG
	1.5	\checkmark
152	1.25 Licher in	
153	1.12	15K MEG
154	1.3	

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RESISTANCE TEST Page 2 Of 10

TABLE 1

FLOOR WIRE NO.	RESISTANCE WITH SHORT AT PATCH/PANEL	MEGGAR TEST
.55	1.2	7K MEG
156	1.2	20K MEG
157	1.15	5K MEG
158	1.2	\checkmark
159	. 1.2	\checkmark
160	1.2	20K MEG
161	1.24	
162	1.14	\checkmark
163	1.24	
164	1.13	<u> </u>
165	1.16	
166	1.22	
167	1.22	
168	1.24	
169	1.13	
170	125	
171	1.22	
172	123	
173	1.25	
174	1.25	20K MEG
175	- 1. 1 *	
176	1.23	4K MEG

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TABLE 1

FLOOR WIRE NO.	RESISTANCE WITH SHORT AT PATCH/PANEL	MEGGAR TEST
/77	1.15	IK MEG
178	1.23	
,79	1.2	\checkmark
180	1.2	
81	1.23	\checkmark
182	1,23	
183	1.24	\checkmark
184	1.6	2.4K MEG
185	1.6	600 MEG
186	1.52	4.5K MEG
187	1.63	
188	1.5	
189	1.62	20K MEG
190	1.63	
191	1.62	20K MEG
	1.0	
193	1.6	\checkmark
19.4	1.63	\checkmark
195	1.6	\checkmark
	1.62	\checkmark
		· · · · · · · · · · · · · · · · · · ·

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TABLE 1

FLOOR WIRE NO.	RESISTANCE WITH SHORT AT PATCH/PANEL	MEGGAR TEST
· •		
		· · · · · · · · · · · · · · · · · · ·
		·····
<u></u>		
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APPENDIX B. INPUT PREAMPLIFIER TEST

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INPUT PREAMPLIFIER TEST

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The purpose of this test is to measure the gain, frequency response and distortion of the custom pre amplifiers. From the patch panel measure the performance of each amplifier channel at the following frequencies and input signal amplitudes. (Distortion at 20, 80 & 200 Hz only)

INPUT AMPLITUDE: 30 mv., 300 mv, 600 mv. INPUT FREQUENCY (Hz)2, 10, 20, 30, 40, 80, 140, 200

HT 2 (HZ) Himplifiers were measured with store THE VIVM RESPONSE DEESN'T GO DOWN THAT NOW

TRESTEQUIRMENT FUNCTION GG. From System 4000 VTVM SN 22965 (MD) 330E D.stortion Bralyzer SN 204-08400 (MD) Scope With two Vertical ignets

AMP	СН	#_	1_
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Exc: Free	itation quency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion * @ 300 mv IN	
	2	880	7			
		COUMU For	3.1/ YOLIS	6.18 VOLIS	······································	
	10	520 mv	3.2 VOLTS	6.6 VOLTS	- <u></u>	
+	← 20	320 mv	3.2 VOLTS	6.6 VOLTS	. 34 %	
_	30	320 mu	3, 2 VOLTS	6.6 VOLTS		
-	40	320 m	3. 2 voirs	6.6 VOLTS		
*	80	320 mV	3. 3 VOLTS	6.6 VOLTS	. 37.	
-	140	320 mv	3,25 VOLTS	6.6 VOLTS		
*	200	320 mv	3.2 VOLTS	G. G VOLTS	. 3%	

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AMP	СН	ŧ	Í,
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Exc Fre	itation quency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion « @ 300 mv IN
	2	880 av Pt P	3 11 VALTS	6.18 VELTS	
-	10	320 mV	32 YOLTS	6. TVOLTS	
	<mark>⊭</mark> 20	320 mV	3. 2 VOLTS	6.6 VOLTS	. 36%
-	30	320mu	3, 2 VOLTS	6.6 v	
-	40	320 mu	3.2 VOLTS	6,60	
*	80	320 mi	3.2 VOLTS	6.6V	.3%
-	140	320 mr	3.2 VOLTS	6.7v	·
*	200	320 mu	3.2 VOLTS	6.65x	. 3
-	- <u></u>				

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AMP	Сн	₽_	3	
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Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion # @ 300 mv IN
4 <u>999 - 1999 - 1999 - 1999 - 1999 - 1999 - 1999 - 1999 - 1999 - 1999 - 1999 - 1999 - 1999 - 1999 - 1999 - 1999</u>			· · · · · · · · · · · · · · · · · · ·	
2	880 mv PtoP	3.11 VOLTS	6.18 YOLTS	
10	320 mv	3.2 VOLTS	6.6 VOLTS	
* 20	320 mv	3.2 VOLTS	6.6 V	. 36%
30	320mu	3. 2 VOLTS	6.6 v	
40	320 m	3.2 VOLTS	6.6V	
* 80	320 mJ	3.2 VOLTS	6.60	.3%
140	320 mv	3.2 VOLTS	G.G.	
* 200	320 m.v	3.2 VOLTS	6.6v	. 37.

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AMP	СН	#_	4_
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Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion # @ 300 mv IN	
2	SEC - PtoP	311 VOLTS	GUE VOLTS		
10	320mv	3.2 VOLTS	6.6 VOLTS		
× 20	320 mV	3.2 VOLTS	6.6 v	. 36%	
30	320 mv	3.2 VOLTS	6.6v		
40	320 mu	3, 2 VOLTS	6.6x		
★ 80	220 m.	3. 2 VOLTS	6.64	. 3%	
140	320 mv	3.2 VOLTS	6.65v		
* 200	320 mv	3.2 VOLTS	6.65v	. 3%	

AMP	СН	₽	5
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Exci Frec	itation quency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion # @ 300 mv IN	
	 2		211 VALTE			
	10	320 mv	3.2 VOLTS	6.6 VOLTS		
+	+ 20	320 mv	3. 2 VOLTS	6.6v	. 3670	
	30	320 mu	3.2 VOLTS	6.6v		
_	40	320 mv	3, 2 VOLTE	6.60		
*	80	320 m.	3. 2 VOLTS	6.60	. 370	
_	140	320 mu	3.2 VOLTS	6.6v		
*	200	320 mv	3. 2 VELTS	6.6v	. 37.	

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AMP	СН	#_	6
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Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion # @ 300 mv IN	
2	PET FLO	311 VOLTS	GIE VEITS		<u> </u>
10	320 my	3.2 VOLTS	6.6 VOLTS		
<mark>₩</mark> 20	320 mv	3.2 VOLTS	6.6v	. 367	
30	320 mu	3.2 VOLTS	6.6v		
40	320 m.v	3.2 VOLTS	6.6v		
* 80	320 m,	3.2 VOLTS	6.60	. 3 %	
140	320 m	3.2 VOLTS	6,6v		
* 200	320 mv	3.2 val75	6.61	. 3%	

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AMP CH #<u>7</u>

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Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion # @ 300 mv IN
Z	3/1 mu	3.11 V6275	6.18 MLTS	·
10	320 mv	3.2 VOLTS	6.6 VOLTS	
<mark>.</mark> ₩ 20	320 mv	3.2 VOLTS	6.6v	.367。
30	320 m.J	3.2 VOLTS	6.6v	
40	320 m	3.2 VOLTS	6.60	
★ 80	320 m	3.2 VOLTS	Gilev	.350
140	320 mv	3.2 VGLTS	6,65V	
* 200	320 ~~	3.2 VELTS	6.65v	. 3%

AMP CH # Z

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output Vith 600mv Input	Distortion * @ 300 mv IN
<u></u>				
2	311 mV	3.11 VOLTS	6,18 VCLTS	
10	320 mv	3.2 VOLTS	6.6 VOLTS	
<u>+</u> 20	320 mV	3.2 VOLTS	6.6v	. 36%
30	320 mu	3.2 VOLTS	6.6v	
40	320 mi	3.2 VOLTS	6.6v	
★ 80	320 mu	3. 2 VOLTS	6.6v	. 37.
140	320 mi	32 VELTS	6.6v	
* 200	320 ~~	3. 2 VOLTS	6.64	. 3%

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AMP	СН	<i>‡:</i>	9
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Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion # @ 30C mv IN	
2	211	311 VALTS	CIE VITE		
10	320 mv	3,2. VOLTS	6.6 VOLTS		
<u>+</u> 20	320 mu	3.2 VOLTS	6.6v	. 36%	
30	320 mu	3.2 VOLTS	6.60		
40	320 mi	3.2 VOLTS	6.6v		
* 80	320 my	3.2 VOLTS	6.6v	. 37.	
140	320 mv	3.2 VOLTS	6.60		
.x 200	320 mv	3. 2 VOLTS	6.6v	. 3.0	

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AMP	СН	ŧ	<u>10</u>
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Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion # @ 300 mv IN	
<u> </u>		211 10 TC	CIC VALTE		
ذ 	<u>3// mv</u>	3.11 V62.5	6,18 VCL/S		
10	320 mv	3.15 VOLTS	6.6 VOLTS		
<mark>≁</mark> 20	320 mv	3.2 VO_TS	6.6v	.367.	
30	320 mJ	3.2 VOLTS	6.6v		
40	320 mv	3.2 V CLTS	6.6v		
* 80	320 mv	3.2 VOLTS	6.6v	.3%	
140	320 mu	3.2 vats	6.61		
* 200	320 mu	3. 2 VOLTS	6.6v	. 37.	

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AMP	СН	# <u>//</u>	

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion # @ 300 mv IN
2	311 nv	3.11 VOLTS	6.18 VOLTS	
10	320 mg	3.2 VOLTS	6.6 VOLTS	
<u>+</u> 20	320 mV	3, 2 VOLTS	6.6v	. 3670
30	320 mu	3.2 VOLTS	6.60	
40	320 mJ	3.2 VCLTS	6.60	
* 80	320 mu	3.2 VOLTS	6.6v	. 3 ??c
140	32C mv	3 2 VOLTS	6,6v	
× 200	320 mu	3.2 VOLTS	6.6v	. 370

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AMP	СН	#	12
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Exc Fre	citation equency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion * @ 300 mv IN
	2	311 mV	3.11 VULTS	6.18 VOLTS	
	10	320 my	3.2 VOLTS	6.6 VOLTS	
	× 20	320 mV	3.2 volts	6.55VOLTS	. 36%
-	30	320 mv	3.2 VOLTS	6.6V	
	40	320 mu	3.2 vo5	6.6v	
-	(80	320 mi	3, 2 VOLTS	6.6v	. 3%
	140	320 mv	3.2 VOLTS	6.60	
*	200	320 m	3, 2 VOLTS	6.6v	. 370
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AMP	СН	#/3

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion * @ 300 mv IN	
2	3/100	311 VOLTS	6.18 VOLTS		
10	320 mil	3.2 VOLTS	6,6 VOLTS		
₩ 20	320 mv	3.2 VOLTS	6.6 v	. 36%	
30	320 mu	3.2 VOLTS	6.6v		
40	320 mV	3.2 VOLTS	6.6v		
★ 80	32Cmu	3.2 VOLTS	6.6v	. 37.	
140	320 mv	3.2 VOLTS	6,6v		
★ 200	320 mu	3.2 VOLTS	6.6v	. 370	

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Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion * @ 300 mv IN	
2	311-11	311 VAITS	G. IR VOLTS		
10	320 mv	3. 2 VOLTS	6.6 VOLTS		
<mark>★</mark> 20	320 m.v	3.2 VOLTS	6.6v	. 3670	
30	320 mu	3.2 VOLTS	6.6v		
40	320 mu	3. 2 VOLTS	6.6v		
* 80	320 mu	3.2 VOLTS	6.60	. 3 %	
140	320 m	3. 2 VOLTS	6.6v		
* 200	320 mu	3. 2 VOLTS	6.6v	. 3%	

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amp ch #<u>15</u>

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Excitation Erequency/Hz	Output with 30 mv	Output With 300my Input!	Output With 600my Input	Distortion 🛪 @ 300 my TN
2	311 mr	311 VOLTS	6.18 VOLTS	
10	320 mu	3. 2 VOLTS	6.6 VOLTS	
* 20	320 mV	3. 2 VOLTS	6.6 v	. 3670
30	320 mu	3.2 VOLTS	6.6v	
40	320 mu	3.2 VELTS	6.60	
★ 80	320 mu	3.2 VOLTS	6,60	.3%
140	320 mv	3. 2 VELTS	6.65V	
* 200	320 mu	3.2 VOLTS	6,65v	. 370

AMP	СН	#_	L	6
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Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion × @ 300 mv IN	
2	311m	3.11 VOLTS	6.18 VOLTS		
10	320	3.2 VOLTS	G. 6 VOLTS		
<u>+</u> 20	320 mV	3.2 VOLTS	6.6 VOLTS	. 34 %	
30	320 mu	3.2 VOLTS	6.6v		
40	320 mu	3. 2 VOLTS	6.60		
⊀ ⁸⁰	320 mJ	3.2 VOLTS	6.6v	.3%	
140	320 mv	3,2 VOLTS	4.6v		
* 200	320 mu	3. 2 VOLTS	6.6v	. 3%	

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AMP	Сн	#	12	
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Exci Freq	tation uency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion * @ 300 mv IN	
	2	311 mx	3.11 VOLTS	6.18 VOLTS		
	10	320 mi	3.2 VOLTS	6.6 VOLTS		
*	20	320 mv	3. 2 VOLTS	6.6 VOLTS	. 347.	
	30	320 mV	3.2 VOLTS	6.6v		
_	40	320 mu	3. 2 VOLTS	6.60		
*	80	320 mu	3.2 VOLTS	Ge, lev	. 3%	
	140	320 mv	3.2 VOLTS	6.6v		
*	200	320 mv	3.2 VOLTS	6.6V	. 37.	

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Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion # @ 300 mv IN
2	311 mv	3.11 VOLT5	6,18 VOLTS	
10	320 mu	3.2 VOLTS	G.G VOLTS	
₩ 20	320 mV	3.2 VOLTS	6.6 VOLTS	. 34%
30	320 mu	3.2 Voz-5	6.6v	
40	320 mv	3. 2 verts	6.60	
* 80	320 mu	3. 2 VOLTS	G. GU	.37.
140	320 mv	3,2 yests	6.6v	
* 200	320 mu	3, 2 VELTS	6.6v	. 37.

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AMP CH 🕴	19
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Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion * @ 300 mv IN
2	3//m/	3.11 VOLTS	6,18 VOLTS	
10	320 a.r	3.2 VOLTS	6,6 volts	
* 20	320 mv	3.2 VOLTS	6.6 volts	. 34%
30	320 mu	32 VOLTS	6.6v	
40	320 mu	3. 2 vol=5	6.6v	
* 80	320 mu	3. 2 VOLTS	6.6v	. 37.
140	320 mv	3.2 VOLTS	6. 6v	
* 200	320 m	3.2 VOLTS	6.60	. 3%

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AMP	СН	#20

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Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion * @ 300 mv IN	
2	31/ my	3.11 VOLTS	6.18 VOLTS		
10	320 mu	3.2 VOLTS	6.55 VOLTS		
* 20	3/8 mv	3. 2 VOLTS	6.55 VILTS	. 34%	
30	320 m	3.2 VOLTS	6,55v		
40	320 mu	3. 2 VOLTS	6.60		
* 80	320 m	3.2 VOLTS	6.60	. 3 7.	
140	320 mV	3.2 VELTS	6,550		
× 200	320 mr	3.2~	6,55v	. 3%	

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion * @ 300 mv IN
2	211	311 VEITE	6 18 101 -	
10	320 mV	3.2 VOLTS	G. G VOLTS	
<u></u> ↔ 20	320 mv	3.2 VOLTS	6,55 volts	. 34%
30	320 mJ	3.2 VOLTS	6.6v	
40	320 mv	3.2 VOL-5	6.6v	
★ 80	320 mJ	3,2VOLTS	6.60	. 3 7.
140	320 mr	3.2 vol-5	6.60	
* 200	320 mi	3.2 VOLTS	6,6v	. 37.

AMP CH #21

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AMP CH # 22

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion * @ 300 mv IN
2	311mu	3.11 VOLTS	6,18 VOLTS	
10	320 mv	3.2 VOLTS	6,6 VOLTS	
<mark>.</mark> ₩ 20	320 mu	3.2 VOLTS	6.6 VOLTS	. 347.
30	320 mv	3.2 VOLTS	6.6v	
40	320 mu	3.2 VOLTS	6.6v	
. € 80	320 mu	3.2 voire	6.60	. 370
140	320 m	3.2 vents	6.64	
* 200	320 mv	3,2 VOLTS	6.6v	. 37.

Ficitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion # @ 300 mv IN
2	31/m	3.11 VOLTS	G.18 VOLTS	
10	320 ml	3.2 VOLTS	6.6 UOLTS	
* 20	320 mv	3.2 VOLTS	6,6 volts	. 34%
30	320 mu	3.2 VOLTS	6.6 V	
40	320 mu	3.2 VOLTS	6.6v	
∢ 80	320 mJ	3.2 VOLTS	6,60	. 3 %
140	320 mr	3.2 VELTS	6.60	
× 200	320 m	3.2 VOLTS	6.6V	. 3%

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AMP CH # 23

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AMP CH #<u>24</u>

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion * @ 300 mv IN	
2	311 mv	3.11 VOLTS	G.18 VOLTS		
10	320 mu	3.2 VOLTS	6.6 VOLTS		
≠ 20	320 mV	3.2 VOLTS	6.6 VOLTS	. 34%	
30	320 m u	3.2 VOLTS	6.6 v		
40	320 mu	3.2VCLTS	6.60		
★ 80	320 mu	3, 2 VOLTS	6.60	. 370	
140	320 mv	3,2 VELTS	6. Lev		
× 200	320 mv	3.2 VELTS	6.6v	. 37.	

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Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion * @ 300 mv IN	
2	311mv	3.11 VOLTS	6,18 VOLTS		
10	320 mv	3. 2 VOLTS	6,6 VOLTS		
<u></u> <i>★</i> 20	320 mv	3.2 VOLTS	6.6 VOLTS	. 34%	
30	320 mu	3.2 VON-5	6.6 v		
40	320 mu	3. 2 VENTS	6.60		
★ 80	320 mJ	3. 2 voits	6,60	. 37;	
140	320 mv	32 VOLTS	6.65v		
* 200	320 m	3.2 VC175	6.65v	. 376	

AMP CH #25

AMP CH	126
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Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion * @ 300 mv IN
2	311 mv	3.11 VOLTS	G.18 VOLTS	
10	320 mv	3. 2 VOLTS	6.6 VOLTS	
* 20	320 mv	3.2 VOLTS	6. 6 VELTS	. 34 %
30	320 mv	3.2 VOLTS	6.6 v	
40	320 mu	3. 2 VOL-S	6.40	
* 80	320 mu	3.2 VOLTS	G.64	. 2 %
140	320 mV	3. 2 VELTE	6.60	
× 200	320 mv	3.2 VCLTS	6.6v	3%

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Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion 🛪 @ 300 mv IN	
2	311 mv	3.11 VOLTS	6.18 VOLTS		
10	320 mv	3.2 YOLTS	6.6 VOLTS		
* 20	320 mu	3. 2 VOLTS	6.6 VOLTS	.34%	
30	320 mV	3.2 VOLTS	6.6v		
40	320 mu	3. 2 VOLTS	6.6v		
* 80	320 mJ	3.2 VOLTS	6.60	. 3%	
140	320 my	3.2 VELTS	6.6v		
× 200	320 mv	3, 2 velts	6,6v	. 3 70	

AMP CH # 28

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion * @ 300 mv IN
2	311 mv	3.11 VOLTS	6.18 VOLTS	
10	320 mv	3.2 VOLTS	6.6 VOLTS	
, 2 0	320 mv	3.2 VOLTS	6,6 VOLTS	.3670
30	320 mu	3.2 vo5	6.6v	
40	325 mv	3.2.V====5	6.6v	
★ 80	320 mu	3. 2 VOLTS	6.6v	. 3%
140	320 my	3.2 VOLTS	6.6v	
* 200	320 ~~	3.2 VOLTS	6.650	. 37.

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AMP	СН	# <u>29</u>
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Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion # @ 300 mv IN	
2	311 mv	3,11 VOLTS	6.18 VOLTS		
10	320 mv	3. 2 VOLTS	6.6 VOLTS		
** 20	320 mV	3.2 VOLTS	6.6 VOLTS	, 347.	
30	320 mi	3.2 VOLTS	6.6V		
40	320 mv	3. 2 VOLTS	6.6V		
* 80	320 m2	3. 2 VELTS	6.60	. 3%	
140	320 00	3.2 VOLTS	6.650		
* 200	320 mi	3. 2 VOLTS	6.65v	. 3%	

 $\left(\begin{array}{c} \\ \end{array} \right)$

AMP CH # <u>30</u>

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300my Input(Output With 600my Input	Distortion 🛪 @ 300 my IN
	1			
2	311 mv	3.11 VOLTS	6.18 VOLTS	
10	320 mv	3.2 VOL75	6.55 VOLTS	
* 20	320 m	3.2 VOLTS	6.55 VOLTS	. 34 %
30	320 mV	3.2 VOLTS	6.55v	
40	320 m	3.2.VOLTS	6.60	
-€ 80	320 mV	3. 2 VOLTS	6.60	. 3%
140	320 mv	3.2 VOLTS	6.60	
* 200	320 mu	3.2 VOLTS	6.6V	. 3%
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AMP	CH	# <u>31</u>
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Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion + @ 300 mv IN
	311 mu	3.11 V0-TS	6.18 VOLTS	
10	320 mv	3.2 VOLTS	G. 6 VOLTS	
× 20	320 mV	3.2 VOLTS	6,6 VOLTS	. 34 %
30	320 mu	3.2 VOLTS	6.6 v	
40	320 mV	3.2 VOLTS	6.6v	
∢ 80	320 m	3.2 VOLTS	6.6v	. 370
140	320 mv	3.2 VOLTS	6.6 v	
* 200	320 m	3.2 VOLTS	6.6V	. 370

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AMP CH # 3	2
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Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion * @ 300 mv IN
2	311 mv	3.11 VOLTS	6.18 YOLTS	
10	320 mr	3.2 VOLTS	6.6 VOLTS	
× 20	320 m	3.2 VOLTS	6,6 VOLTS	. 34 %
30	320 mv	3.2 VOLTS	6.6 v	
40	320 mJ	3.2 VOLTS	6.6v	
. € 80	320 mv	3.2 VELTS	6,60	. 3%
140	320 mv	3.2 VELTS	6.6v	
× 200	320 mu	3.2 VOLTS	6.6v	. 3%
	320 mu	J. Z. VILIS	(9, 6 V	. 3%

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AMP CH #____

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Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion × @ 300 mv IN
	Output with 30 mv Input %	Output with Output 30 mv With Input % 300mv Input	Output with 30 mv Output With Output With Input % 300mv Input

AMP CH #____

Excitation Frequency/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion « @ 300 mv IN
2				
10				
* 20				
30				
40				
. € 0				
140				
- x 200				<u></u>

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AMP CH #____

Excitat Frequen	ion cy/Hz	Output with 30 mv Input %	Output With 300mv Input	Output With 600mv Input	Distortion * @ 300 mv IN	
2						
* 20						
30				,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,		
40						
* 80						
140						
<u></u> + 200				<u></u>		

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APPENDIX C. GROUNDING TEST

GROUNDING TEST

The purpose of this test is to investigate the adequacy of the system A.C. ground. Configure the system as shown in figure 2. With the H. P. system running, make the following A.C. Voltage measurements.

H.P. Rack to Preamp Rack	VOLTAGE <u>11.5 mill-volts</u>
H.P. Rack to Power Amp Rack	1.6 MV
H.P. Rack to Test Stand	34 mv
Preamp Rack to Power Amp Rack	4.7 mV
Preamp Rack to Test Stand	3C mV
Power Amp Rack to Test Stand	39 mV 7.7 mV D.C.

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Connect a ground strap between the following points and repeat the measurements.

	VOLTAGE	
H.P. Rack to Preamp Rack	3.8 mv	22 mv P.C.
H.P. Rack to Power Amp Rack	1.2 m	1.4 mv D.C.
H.P. Rack to Test Stand	11 MV	10 Mr D.C.
Preamp Rack to Power Amp Rack	2.9 mv	very low D.C
Preamp Rack to Test Stand	9.3 mv	NO D.C.
Power Amp Rack to Test Stand	1.1 mv	3.6 D.C.

CROUND TEST





TEST CONDITIONS

State State State State State State

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- o Sine Sweap ∅ to 200 Hz
- o All Power Amps On
- o All Shakers @ 1/2 Power
- o All input and power supplies connected through patch panel

TESTEQUIPMENT 8600 A Digital Multimeter SN 585307 (Flake)

APPENDIX D. POWER AMPLIFIER TEST

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POWER AMPLIFIER TEST

TREST EQUIPMENT Function Geni

The purpose of this test is to determine the frequency response, distortion, and phase shift of the power amplifiers. Connect the equipment as shown in figure <u>3</u> and measure each amplifier performance at the following fequencies and power settings.

O-SC: PE

E'STOKTION AMP

VOLT METER

Input frequency 2, 10, 20, 30, 40, 80, 140, 200 output power (WATTS) 10, The measure the amplifier distortion with shaker loaded to .5 and lg. at 20, 100 and 200 Hz

4000 VTVM 330 B Distortion Analyzer Scope SIGNAL GEN. Power AMP FRED COUNTER

TABLE 3 51 1390

50 WATTS 100 INPUT WATTS 10 WATTS FREQUENCY 8.1 volts 3.11 volts 5.65 volts 2 8.7 volts 4. 6 volts 11: 6 volts 10 9.2 volts 4.8 volts 12.5 volts 20 9.0 volts 12.5 volts 30 4.8 yolts 9.0 volts 12.5 volts 40 4.7 volts 9.2 volts 12.5 volts 4.8. volts 80 9.0 volts 12,5 velts 4.8 volts 140 9.0 volts 12.5 volts 4.8 volts 200

OUTPUT POWER

50

DISTORTION @

100

PHASE SHIFT @

INPUT FREQUENCY	\$	3	
20	. 3 to . 4 7	.49.	76
100	32%	. 470	0•
200	. 370	. 35%	0.

SN 1370



I NPUT FREQUENCY	10 WATTS	50 MATTS	WATTS
2	2.7 volts	5.4 VOLTS	7.4 VOLTS
10	4.1 volts	8.2 VOLTS	11.0 VOLTS
20	4. H volts	8.7 VOLTS	12.0 VOLTS
30	4.4 volts	8.7 VOLTS	12,0 VOL75
40	4.3 volts	8.7 VOLTS	12.0 VOLTS
80	4.4 volts	8.7 YOLTS	12.0 VOLTS
140	4.4 volts	8,7 VOLTS	12.0 VOLTS
200	4.4 volts	8.7 VOITS	12.0 VOLTS

OUTPUT POWER

56

,00

DISTORTION @

PHASE SHIFT @

INPUT FREQUENCY			
20	.470	. 4%	7° phase so
100	.3470	.35%	0"
200	. 34%	. 370	0.

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TABLE 3

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INPUT FREQUENCY	10 WATTS	50 WATTS	100 WATTS
2	27 YOLTS	5,6 VOLTS	7.7 VOLTS
10	40 VOLTS	8.4 VOLTS	11.5 VOLTS
20	4.2 VOLTS	8.8 YOLTS	12.0 VOLTS
30	4.2 VOLTS	8.8 VOLTS	12.0 VOLTS
40	4.2 VOLTS	8,8 VOLTS	12.0 VOLTS
80	4.2 VOLTS	8.8 VOLTS	12.0 VOLTS
140	4.2 VOLTS	8.8 VOLTS	12.0 VOLTS
200	4.2 VOLTS	8,8 VOLTS	12,2 VOLTS

	50	00		
	DISTORI	TION @	PHASE	SHIFT @
INPUT FREQUENCY			*	-
20	.6 to .7 %	. 470		70
100	.37.	, 35 %		0°
200	. 32.	. 32 70	······································	0°

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OUTPUT POWER

тавle 3 511 140

		OUTPUT POWER	
INPUT FREQUENCY	10 WATTS	50	
2	2.9 volts	6.0 volts	7.9 volts
10	4.2 volts	8,8 volts	11.5 volts
20	4.4 volts	9.2 voHs	12.2 vo/75
30	4.4 volts	9.2 volts	12.0 volts
40	4,4 volts	9.2 volts	12,0 voits
80	4,4 volts	9.2 volts	120 volts
140	4,4 velts	9.2 volts	122 volts
200	4.4 voits	9.2 volts	12.2 volts

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100

DISTORTION @

PHASE SHIFT @

INPUT FREQUENCY			
20	476	.570	7°
100	47.	.670	0 '
200	.370	.4670	0°

APPENDIX E. FREQUENCY SYNTHESIZER CALIBRATION RECORD

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PERFORMANCE TEST CARD

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Hewlett-Packard Model 3320A/B Frequency Synthesizer			Test Performed By
Serial No. <u>/532 A O / 586</u>			Date
Frequency Accuracy			
Vernier Out			
1 MHz 12.22 MHz 1.10 MHz 00.01 MHz	.999990 MHz 12.219878 MHz 1.099989 MHz 89.99909 æ	1,000000 12.219992 2099999 20.00007	1.000010 MHz 12.220122 MHz 1.100011 MHz 100.00100 عد
Vernier In			
00_0150 MHz 12_9999 MHz 1000 kHz Range 100 kHz Range 10 kHz Range 100 Hz Range	14.000 kHz 12.9989 MHz	15,095 12999986 1.30000 13000 13000 1.300	16.000 kHz 13.0009 MHz
Harmonic Distortion			
Not 10 kHz			> - 60 dB
Checker 129.9 kHz		·····	> - 50 dB
150 kHz			> - 50 dB
1259 kHz		·	>-40 dB >-40 dB
7 MHz			> 40 dB
12.99 MHz			> - 40 dB
Spurious			> - 60 dB or - 110 dBm
Signal to Phase Noise Not Charked			> - 40 dB
3320A Amplitude Accuracy			
50 Ohm load Open circuit	0.9 V rms 1.8 V rms		1.1 V rms 2.2 V rms
3320B Amplitude Accuracy		-	
50 Ohm laed Open circuit	4.975 V rms 9.95 V rms	3.01	5.025 V rms 10.05 V rms
Entrance Branne			
22204	0.0		4.1 cm
	- 0.6 cm	401	។ របញ្
3320B, 0.01 Hz-10 Hz	- 0.2 cm	<u> </u>	+ 0.2 cm
	(man 1) ()-	6970 to 7034	

Adjusted Errors: Adjusted Errors: (Para, 5-22(e)): C in the formula A = B + C - D

12.99 MHz	_01 MHz	1299 kHz	1 kHz	129.9 kHz	.1 kHz	12.99 kHz	.01 kHz	1299 Hz	10 Hz
- 2.15	C	. 86	14	- , 14	14	14	2.73	14	2.43

			CAL	IBRATI NE BROU	ON REC		3		PAGE	/ 01_3
INSTRUMENT		OW	INER //	CAF			DATE			
HANGACIURACY -	Synthesizer	MC		277			SERIA	U NUMBER	12-79	<u></u>
N.	P			3320	08			1532	ROIS	86
TECHNICIAN	Fran	DA	TE OF LAST	(ALIBRATIC) N 		NEXT	DUE DATE		
AMBIENT TEMPERATUR	RE	ни	MIDITY	10	7		PROCI	EDURE	~	
ADJUSTMENT REQUIRE	D REMARKS	k		700	PARTS REG	UIRED	REMARKS	Many a	w/cares	
VES NO					D YES					
				DA	TA					
NOMINAL READING OF ITEM BEING CALIBRATED	INITIAL READING OF CALIBRATING EQUIPMENT	ALGEBRA SUBTRACT	IC ERROR B FROM A	SPECIFIED OF ITER CALIBR	ACCURACY M BEING ATED %	ACCE	PTABLE ROR	ALGEBRA GREATE ACCEPTAE	IC ERROR R THAN BLE ERROR	FINAL READING AFTER REPAIL OR ADJUSTMEN
		+	-	1	:		r	YES	NO	1 I
14-	10000 19 1150	·	<u> </u>	'	·		<u></u>	<u> </u>	<u> </u>	····
2 Hz	499996 1100							+	1	
SHZ	200000 1100		Inst	umen	+ me	s Ma	inta	teres	Socis	
10 H2	100000 MSR		with	410	folloc	Viag P	xcear	las :	1	
20 Nz	5000/ MSEC		He	maria	= Dist	tra	Spuri	ous, an		
30 Hz	33333 MSPC		5	ana/ - ,	4. ph	ase	Voise	not a	Arche	/
HO HZ	25000 4 sec		d	he to	a lace	F or	and and	er te	574	
50 Hz	2000/ 41500			Quipm	بمحبر					
60Hz	16666 MSA		(
80 Hz	12500 usec							ļ	ļ	
100 Hz	10000 use		ļ						ļ	
120 HZ	833345a			s f 					<u> </u>	
140 Hz	7142 MSEC		 						<u> </u>	
200 Hz	5000 USA				i			1	<u> </u>	
						<u></u>		_ <u>_</u>	<u> </u>	
			<u> </u>							
فتشتقه ومنواد والموا			1				<u></u>		1	ويتقوي ويتعاونه
				EQUIPME	NT USED) 				
DESCRIP	TION, CALIBRATION DA	TE AND AG	5ENCY			DESC	IPTION CA	LIBRATION D	DATE AND A	GENCY
5245L O	unter			504-	03969	, 	6-2	2-29		<u> 78</u>
5458 Sco	#E				0775		6-7	-79		786
L Play	- 14			02	K439		9-20	-79		
885.88 DiA	Yollmeter				195		<u>9-6-</u>	79		- /ut
<u>93/8 RH</u>	Siff. Volte	eter_		3	9/		<u>5-3-</u> 2	<u> </u>		Muk
1049A The	mal Canro	70			002.38		7-3/-	79		MP
3550 VHF	KTTCANA For		··		0/743	9	<u>5-8-7</u>	7		
3400A RHS	Voltmeter			12/	*1919/05		0-12-	17		102

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14 18 1

I Certify that this Calibration is Traceable to and Compatible with National Bureau of Starto

Supervisor Calibration Laboratory

Attenuator Accuracy, 3320B (Para, 5-24(d)): D in the formula A = B + C - D

+ 15.00 dBm + 5.00 dBm - 5.00 dBm - 15.00 dBm - 25.00 dBm - 35.00 dBm - 45.00 dBm	0.998 V dc 0.996 V dc 0.994 V dc 0.992 V dc 0.990 V dc 0.988 V dc 0.986 V dc 0.986 V dc	<u>999</u> <u>1.000</u> <u>999</u> <u>988</u> <u>988</u> <u>988</u> <u>997</u> <u>998</u>	1.002 V dc 1.004 V dc 1.006 V dc 1.008 V dc 1.010 V dc 1.012 V dc 1.014 V dc
- 55.00 dBm - 65.00 dBm	0.984 V dc 0.982 V dc		1.014 V de 1.016 V de 1.018 V de

Attenuator Frequency Response, 3320B Record Readings (Para, 5-26(d)); B in the formula A = B + C - D

	Record Readings	(Step d):					
	12.99 MHz	.01 MHz	1299 kHz	1 kHz	129.9 kHz	12.99 kHz	1299 Hz
+ 15		1489	-299_	-999	<u>· 799</u>	1.000	1999
+ 5	<u></u>	1.001	1.001	1.001	1.001	1.001	1.001
- 5		1.001	1.000	1.000	1.40	1.00	1.000
- 15		1.001	1.00/	1.001	1.001	1.00/	1.001
- 25		1.000	1.000	1.001	1.000	1.000	1.000
- 35	<u> </u>	1.000	1.000	1.000	1.000	1.000	1.000
- 45		1.000	1.000	1.001	1.000	1.000	1.001
- 55	<u> </u>						
· 65							
		6	1	1.	Į	1	

Calculated Error (Para, 5-26(h)): A in the formula A = B + C - D

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_	12.99 MHz	.01 MHz	1299 kHz	1 kHz	129.9 kHz	12.99 kHz	12.99 Hz	Tolerance
+ 15		_0	186	14	14	<u>86</u>	14	± 5 mV
+ 5								± 5 mV
- 5				{				± 12 mV
- 15								± 12 mV
- 25						[± 23 mV
- 35								± 23 mV
- 45								± 23 mV
· 55								± 45 mV
- 65								± 45 mV

